

DIAGNOSTIC BENCH



MODULAR PRODUCT

modular product dedicated to the test, measurement, fault-finding and repair of both analogue and digital electronics, at component or board level.

TESTING AND DIAGNOSTIC OF COMPONENTS UNDER
POWER-ON CONDITIONS
POWER-OFF CONDITIONS



IMPROVE PROCESS
INCREASE
PRODUCTIVITY

MULTI DIAGNOSTIC BENCH

Replacing faulty industrial technologies for new ones is wasteful, unnecessary, and aggravates the E-waste issue



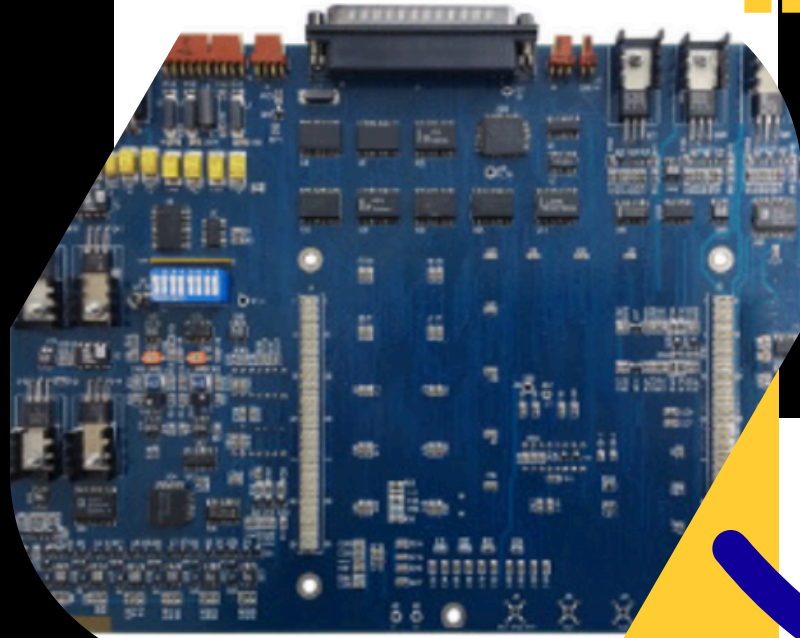
REPAIR IT!



MASTERING AUTOMATE QUALITY

Integrated hardware and software solutions allow user to take control over their electronic maintenance requirements, automate quality tests on new products and generate schematics for legacy equipment

IMPROVE PROCESS
INCREASE
PRODUCTIVITY

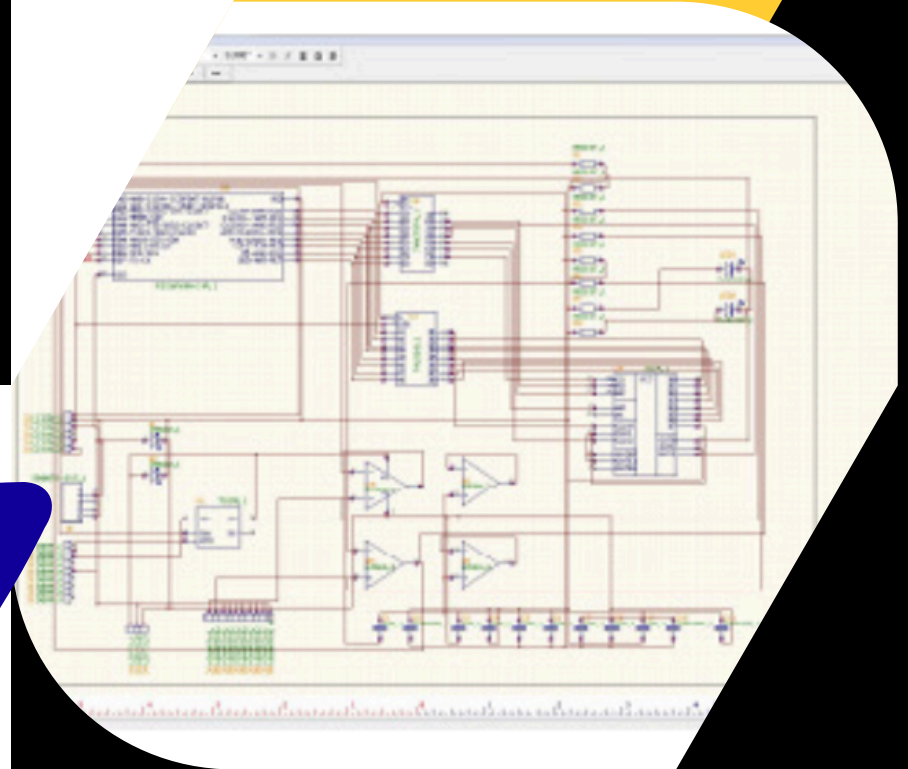


MAIN FUNCTIONS

“ FROM YOUR PCB TO SCHEMATICS!
THE EFFICIENCY IN THE
MAINTENANCE AND REPAIR OF
ELECTRONIC PCBs CAN BE
COMPROMISED BY THE LACK OF
CIRCUIT DIAGRAMS. ”

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BENCH



KEY BENEFITS

- Reduce fault finding time
- Replace less components
- Reduce PCB scrappage
- Generate professional circuit diagrams
- Stop and resume the process at any time

LEARNS CONNECTIVITY

THROUGH CLIPS AND CONNECTORS
LINKED BY THE OPERATOR TO EVERY
DEVICE ON THE PCB

GENERATES A NET LIST

LIST OF COMPONENTS
AND INTERCONNECTIONS

CREATES A CIRCUIT DIAGRAM

BY A VERY EASY AUTOMATED PROCESS

**A SIMPLE TO USE
SYSTEM DESIGNED
FOR THE
GENERATION OF
SCHEMATICS
FROM A SAMPLE
BOARD**

THE SOFTWARE

SAVE TEST RESULT



GENERATE REPORT



DESIGN YOUR INSTRUMENT



SAVE INSTRUMENT SETTING



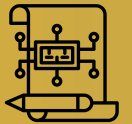
SHARE KNOWLEDGE



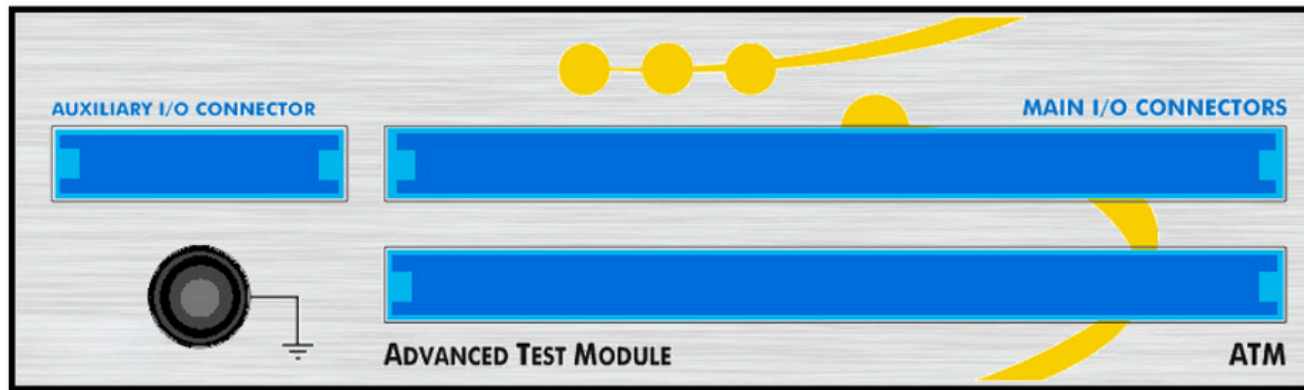
ADD MEDIA



ADD SCHEMATIC

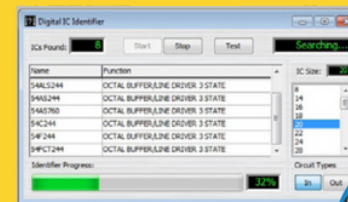


ADVANCE TEST MODULE (ATM)

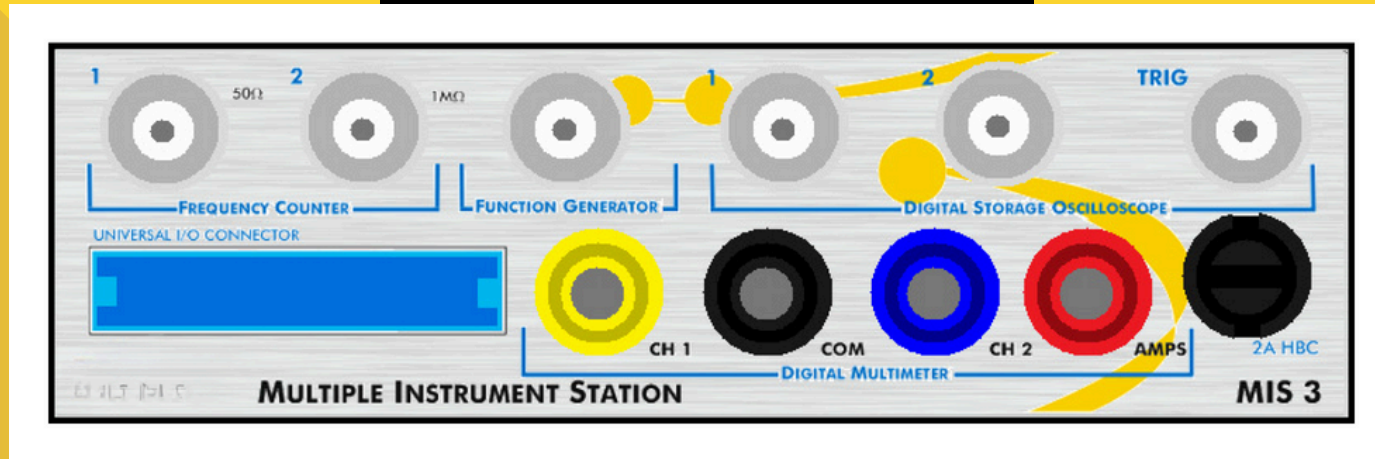


The ATM is a solution designed for the test and diagnostics of all digital ICs and PCBs from all logic families, including TTL, CMOS, LVTTTL and ECL. The module offers power on and power off tests, either in or out of circuit. With high specifications and up to 2,048 channels, the module is ideal for both component and PCB testing.

- In-circuit functional testing (all logic families)
- Out-of-circuit functional testing
- Board level testing (voltage drive/sense, V-I signature) · Graphical generator for custom test vectors
- Connections, voltage, thermal and V-I signature tests · IC identification of unknown parts
- Short locator



MULTIPLE INSTRUMENT STATION (MIS 3)

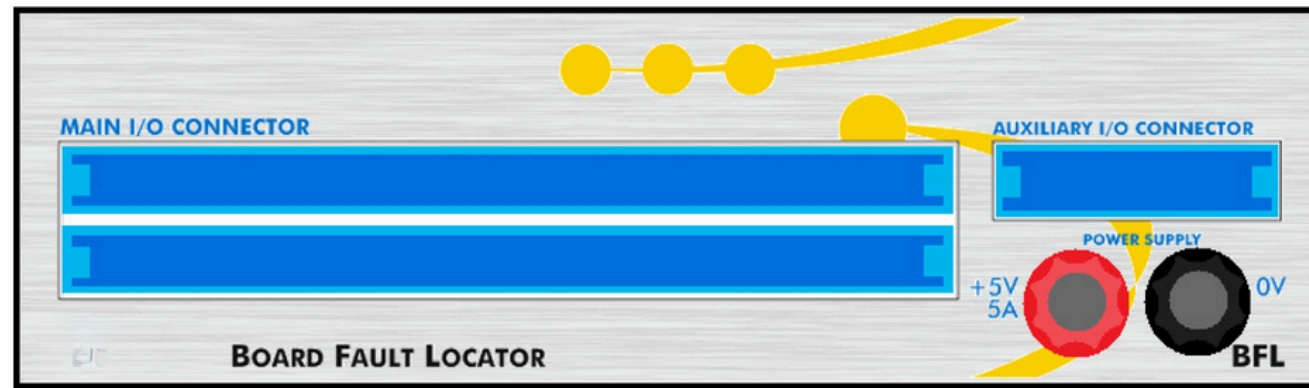


Design Mode allows custom instruments to be created for each individual application and provides an ideal platform for computer based training (CBT) through the highly innovative combination of hardware and software. The sophisticated software can remember unlimited test configurations, controlled by access levels with password protection, so that each operator can save their instrument settings and recall them in seconds.

- Digital Storage Oscilloscope
- Floating Digital Multimeter
- Frequency Counter
- Auxiliary Power Supply
- Function Generator
- Quad Programmable Analogue I/O
- Quad Digital I/O
- Test Flow Manager
- Automated Fault-Finding Sequences
- Customisable Instruments

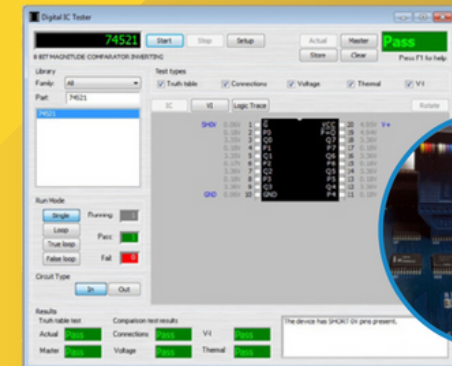


BOARD FAULT LOCATOR (BFL)

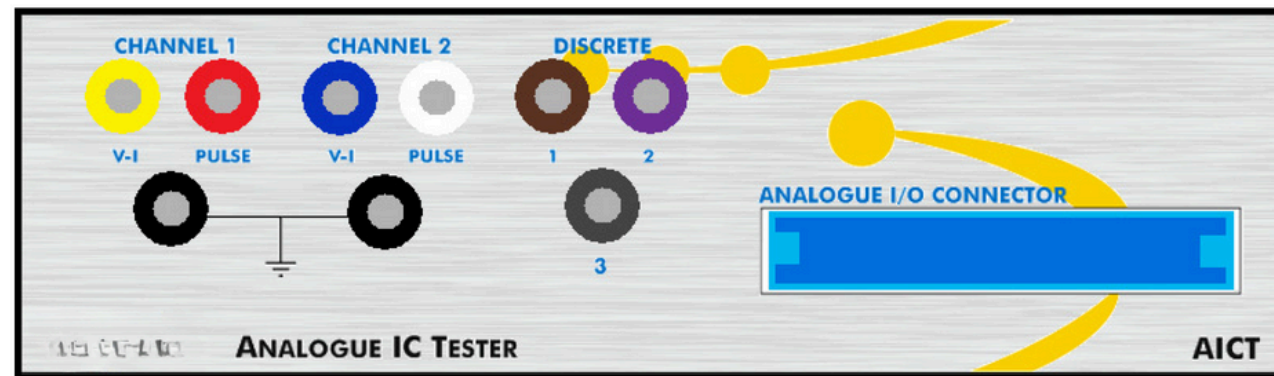


The BFL is aimed at testing TTL/CMOS digital ICs. With 64 test channels, it offers functional testing (in-circuit/out-of-circuit), connections and voltage tests as well as V/I analysis and thermal test. Up to 4 modules can be combined together to offer 256 test channels.

- In-circuit functional testing (TTL/CMOS)
- Out-of-circuit functional testing
- Graphical generator for TTL/CMOS test vectors
- Connections, voltage, thermal and V-I signature tests
- IC identification of unknown parts
- Short locator



ANALOGUE IC TESTER (AICT)

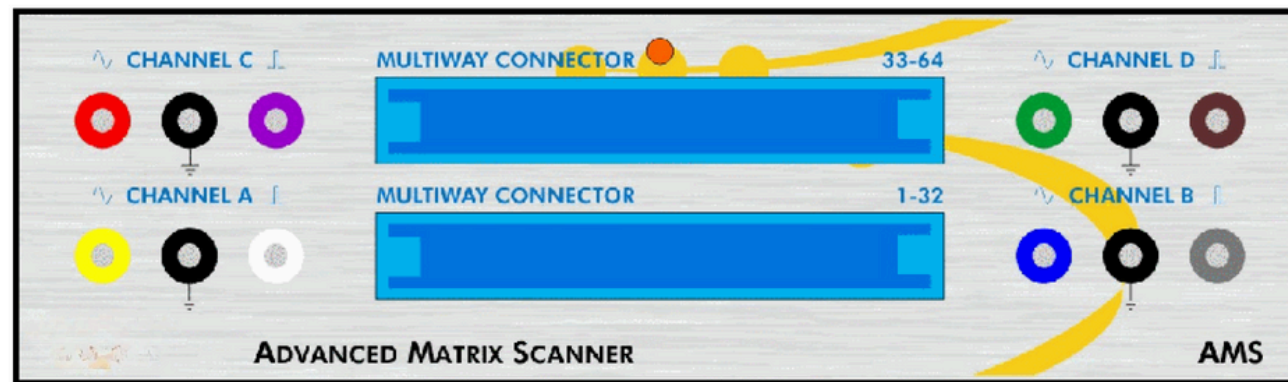


The AICT allows in-circuit functional testing of analogue ICs and discrete components. All common analogue devices can be tested as they are configured on the PCB. The AICT also includes a fully configurable V/I tester equipped with a pulse generator to test gate-activated devices.

- In-circuit functional testing of analogue ICs
- In-circuit functional testing of discrete components
- Connections and voltage tests
- V-I signature tests
- Matrix V-I tests
- Dynamic tests for gate-activated devices

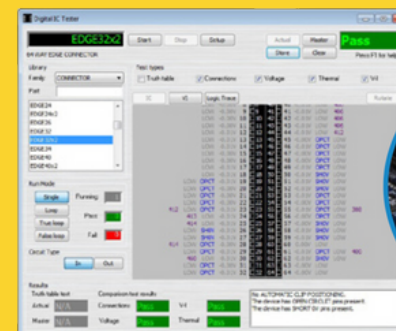


ADVANCE MATRIX SCANNER (AMS)

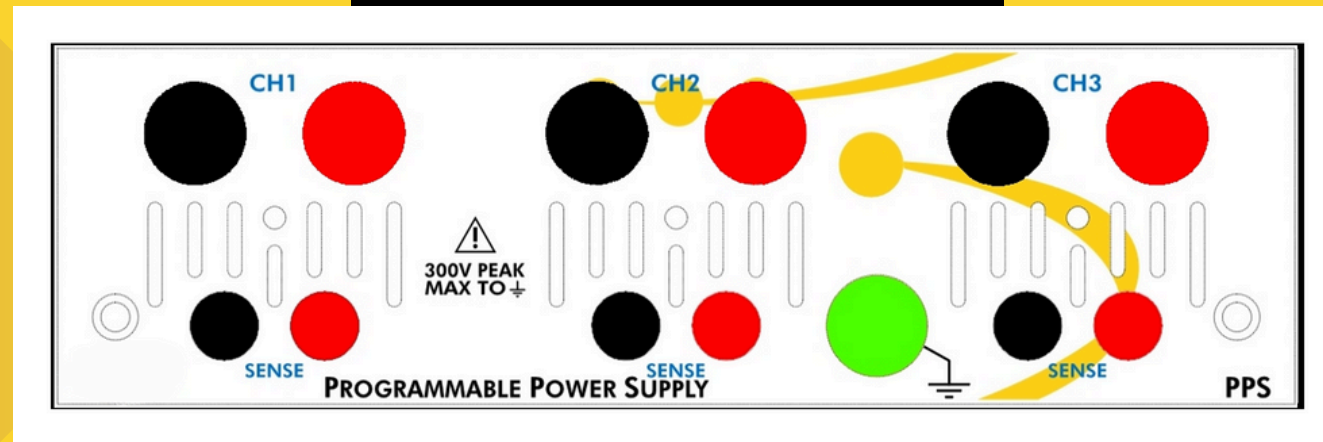


The Advanced Matrix Scanner uses a novel approach to V/I signature testing, the SYSTEM 8 AMS increases test coverage by varying the frequency of the test signal to observe the DUT's (Device Under Test) response over a frequency range. This can lead to finding faults not detectable with other instruments.

- V-I signature tests with sweeping frequency
- V-I signature tests (static frequency)
- Dynamic tests with pulse outputs
- Multi-reference V-I signature tests (Matrix V-I)



PROGRAMMABLE POWER SUPPLY (PPS)



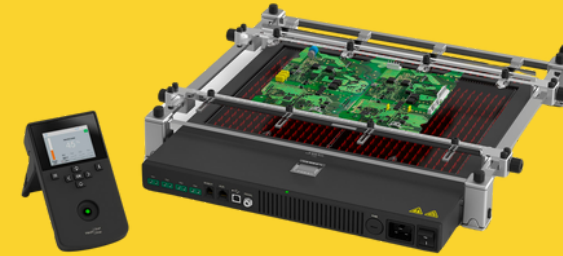
The Programmable Power Supply (PPS) is ABI's most ambitious power module developed for the SYSTEM 8 range. Over 35 years of excellence in product design and manufacturing were applied to the making of this USB driven, versatile unit that suits various test and measurement scenarios. From low to medium volume production test, through to predictive/corrective and PCB troubleshooting tasks.

- **Isolated Voltage Tracking** – Channels are set equal to the group's voltage limit but have independent current control. This can be used to generate tracking bipolar voltages or tracking unipolar voltages relative to different grounds.
- **Power Sequencing** – Channels respond to a group On/Off control.
- **Voltage Stacking** – When voltages above 40V are required, or higher currents (8A MAX) channels can be externally wired in series. The group's set voltage will be divided equally between all members of the group to make efficient use of each channels power envelope and the group's current limit will be applied to all members equally.
- **Parallel** – When currents above 8A are required channels can be externally wired in parallel. The group's set current limit will be divided equally between all members of the group to make efficient use of each channels power envelope and the group's voltage limit will be applied to all members equally.

PRODUCTIVE TOOLS



Most efficient solution
FAE only operates when soldering and features a unique vacuum system integrated into the stand.



Most efficient solution
PCB HOLDER
Integrated system



5 1/2 DIGIT HIGH PERFORMANCE BENCH/PORTABLE MULTIMETER

- Internal rechargeable batteries for true portability
- Dual display and dual measurement capability
- 1908 | 1908P
- High accuracy and resolution: 0.02%, 1 μ V, 1mW, 100nA, 0.01Hz, 10pF
- Frequency, capacitance and temperature measurements
- Wide range of maths and data logging functions
- USB, RS232, GPIB* and LAN (LXI) interfaces



Keep your eyes on the PCB while you're performing a test. Activate the SmartSwitch when you are ready to move on.

MILITARY AREA ENHANCEMENT CAPABILITY



MAINTENANCE

TRAINING AND CERTIFICATION

We are also committed to meeting every customer's training needs. We offer a range of training courses, complete with hands-on opportunities, which can be delivered in house or on-site.



EDUCATION

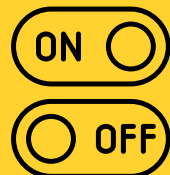


MODULAR PRODUCT

modular product dedicated to the test, measurement, fault-finding and repair of both analogue and digital electronics, at component or board level.



TESTING AND DIAGNOSTIC OF
COMPONENTS UNDER
POWER-ON CONDITIONS
POWER-OFF CONDITIONS



WHY CHOOSE US?



LOCAL SALES SUPPORT

Direct access available to technical support our engineering team based in Jakarta Indonesia



AFTER SALES SUPPORT

Stay current with free upgrades to software and maintenance releases.



INNOVATION

The system is based on an ongoing commitment to quality, professional fulfillment of duties and constant expansion and development

